

EVO® MA/LS series and ΣIGMA™ – Chamberscope and Downscopes

Authors: Dr. Veronika Kugler, Dr. Stewart Bean

Date: September 2008

Introduction

The throughput of the scanning electron microscope can be limited by the need to find small features on a large specimen. 'Chamber' and 'Down' scopes can be used to give a clear internal view of the SEM chamber and are designed to assist the operator with specimen orientation and navigation.

Several ports may be used to mount the chamberscopes and downscopes to provide various views of the specimen. The 'Chamber' and 'Down' scopes may be mounted from a selection of positions on the instrument vacuum chamber.

- **Chamberscope** – mounted on the chamber door (Figures 1 & 2).
- **Downscopes** – mounted on the 20 or 35 degrees ports (Figures 3 & 4).
- **Side-mounted chamberscope** – mounted on the 72 or 127 mm diameter accessory ports (Figures 5 & 6).



Both chamberscopes and downscopes are available with a "Picture In Picture" (PIP) optional facility to provide simultaneous microscopy and chamber views.

Application areas

- **Materials Analysis**
All large specimens, e.g. engineered parts and printed circuit boards.
- **Life Science**
All wet specimens, e.g. specimens that are mounted on the Coolstage

Customer benefits

The benefits to the customer include:

- Rapid visualisation of specimen orientation in the vacuum chamber
- Increase throughput and efficiency by reducing time to locate specific features on large specimens



Figure 1:
Chamberscope



Figure 3:
20 degrees Downscope



Figure 5:
Side-mounted
Chamberscope
(127 mm version)



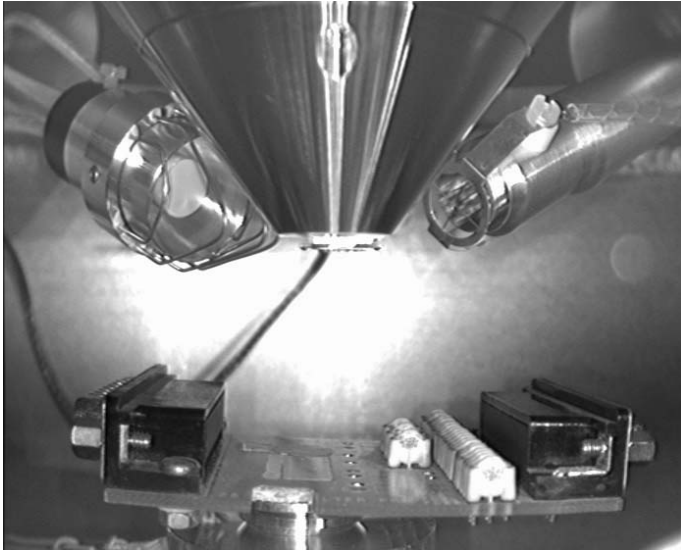


Figure 2:
Chamberscope
Internal view

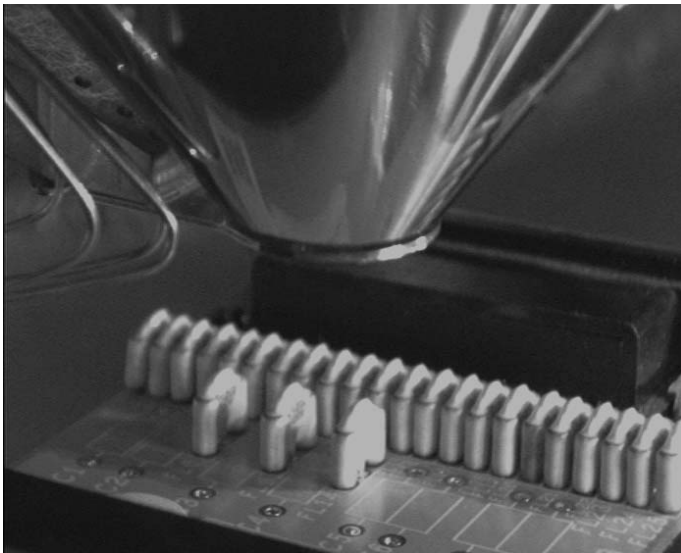


Figure 4:
20 degrees Downscope
Internal view

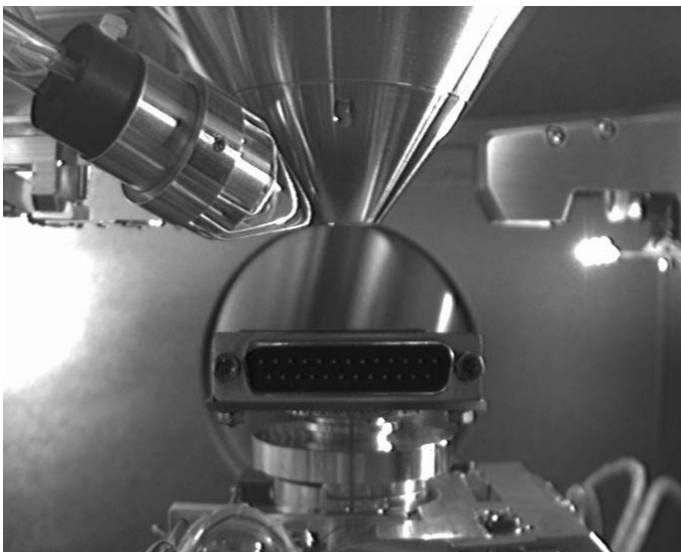


Figure 6:
Side-mounted
Chamberscope
Internal view

Configuration

Compatible with:

- EVO® MA10, MA15 and MA25
- EVO® LS10, LS15 and LS25
- ΣIGMA™

The products available are:

- Chamberscope
- Side-mounted Chamberscope
- 20 degrees Downscope
- 35 degrees Downscope

All available in Picture in Picture (PIP) variants.

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Carl Zeiss NTS GmbH

Carl-Zeiss-Str. 56
73447 Oberkochen
Germany
Tel. +49 73 64 / 20 44 88
Fax +49 73 64 / 20 43 43
info@nts.zeiss.com

Carl Zeiss NTS, LLC

One Corporation Way
Peabody, MA 01960
USA
Tel. +1 978 / 826 1500
Fax +1 978 / 532 5696
info-usa@nts.zeiss.com

Carl Zeiss NTS Pte. Ltd.

50 Kaki Bukit Place #04-01
Singapore 415926
Singapore
Tel. +65 65 67 / 30 11
Fax +65 65 67 / 51 31
info.sea@nts.zeiss.com

Carl Zeiss NTS Ltd.

511 Coldhams Lane
Cambridge CB1 3JS
UK
Tel. +44 12 23 41 41 66
Fax +44 12 23 41 27 76
info-uk@nts.zeiss.com

Carl Zeiss NTS S.a.s.

Zone d'Activité des Peupliers
27, rue des Peupliers -
Bâtiment A
92000 Nanterre
France
Tel. +33 1 41 39 92 10
Fax +33 1 41 39 92 29
info-fr@nts.zeiss.com

www.zeiss.com/nts



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